

## Search Notes



**Application/Control No.**

10/657,261

**Examiner**

Khai M. Nguyen

**Applicant(s)/Patent under Reexamination**

KIM ET AL.

## Art Unit

2617

SEARCHED

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

## INTERFERENCE SEARCHED

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner